

ALAN L. WERTHEIMER

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PROFESSIONAL PREPARATION:

University of Rochester, Rochester, NY Optical Engineering, BS, 1968

University of Rochester, Rochester, NY Optical Engineering, PhD, 1974

APPOINTMENTS:

Consultant to Mote Marine Laboratory, Sarasota, FL, March 2013 – present

Member of Advisory Committee, University of Rochester,

Hajim College of Engineering, Rochester, NY, January 2010 - present

Consultant for Digital Globe, Rochester, NY, May 2010 - December 2011

Chief Technology Officer – ITT Geospatial Systems, Rochester, NY, August 2008 to May 2010
(formerly Kodak Space Systems Division)

Head of Optics Group – ITT, Rochester, NY, June 2006 to August 2008

Subcontract Technical Manager - ITT, Rochester, NY, September 2000 to June 2006

Technical Director, Dynamic Imaging / Kodak, Rochester, NY, Sept 1997 - September 2000

Staff Member/Group Leader, Kodak Space Systems, Rochester, NY August 1982 – Sept 1997

Adjunct Professor, Rochester Institute of Technology, Rochester, NY Sept 1982 – June 1984

Group Leader, Leeds and Northrup, North Wales, PA, March 1974 - August 1982

Optical Lens Designer, Itek Corporation, Lexington, MA, June 1968 - September 1969

PUBLICATIONS/PATENTS:

Closely Related

1. Wertheimer, A L. 1981, U.S. Patent # 4,265,538, Optical Sample Cell for Light Scattering Measurements Using Low and High Angle Scattering, Issued May 5, 1981
2. Wertheimer, A L and Wilcock, W L. 1976. Light Scattering Measurements of Particle Distributions. Applied Optics 15, pp 1616-1620.
3. Wertheimer, A L. 1976 . Development of Instrumentation to Detect Bacterial or Fungal Growth in Intact Final Containers of 25% Normal Serum Albumin (Human), "Final Technical Report on FDA Contract 223-75-1001, July, 1976.
4. Wertheimer, A L and Pfisterer, Jr. G J. 1980. Optical Based Microprocessor Controlled Stack Particulate Monitor, Proceedings of SPIE, Vol. 230
5. Wertheimer, A L 1989. Design of a Diagnostic Radiographic Imaging System for Space Applications," Space Studies Institute Symposium, May 1989.

Five Other Significant

1. Wertheimer A L, et.al, 2004. Design and Performance of a Large Aperture, High-Sensitivity Dynamic Wavefront Sensor, OSA Annual Meeting, October
2. Wertheimer, et al. 1996. "Calibration and Use of an Off-Axis Test Set for 1/100 Wave RMS Ellipsoidal Mirrors, OSA Annual Meeting, October 1996.
3. Wertheimer, A L. and Dey, T. 1994. Wide Range, High Accuracy White Light Piston Sensor for Segmented Optics," Optical Engineering, Sept. 1994.
4. Wertheimer, A L, et.al, 1978, Optical Measurements of Particulate Size in Stationary Source Emissions, EPA Symposium on Advances in Particulate Sampling and Measurement.
5. Wertheimer, A L, and Givens, M P. 1974. Contour Visualization using Coherent Optical Systems, Proceedings of SPIE, Vol 45.

GRADUATE ADVISORS:

M. Parker Givens – University of Rochester

Brian J. Thompson – University of Rochester